Micromagnetics on curved geometries using rectangular cells: error correction and analysis

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# Outline

- Staircase artifact
- 1D correction
- General case
  - Local subgrid
- Correction tests
  - Edge mode resonance
  - Vortex expulsion
- Analytic model





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$$\begin{aligned} \mathbf{E} \mathbf{mag field} \\ \mathbf{H}_{\text{demag}}(\mathbf{r}) &= -\frac{1}{4\pi} \int_{V} \nabla \cdot \mathbf{M}(\mathbf{r}') \frac{\mathbf{r} - \mathbf{r}'}{|\mathbf{r} - \mathbf{r}'|^3} d^3 r' \\ &+ \frac{1}{4\pi} \int_{S} \mathbf{\hat{n}}(\mathbf{r}') \cdot \mathbf{M}(\mathbf{r}') \frac{\mathbf{r} - \mathbf{r}'}{|\mathbf{r} - \mathbf{r}'|^3} d^2 r' \end{aligned}$$

Assume  ${\bf M}$  uniform in each cell gives

$$\langle \mathbf{H}_{\text{demag},i} \rangle = -\sum_{j} N_{i,j} \mathbf{M}_{j}.$$

where formulae for  $N_{i,j}$  are given in

Newell, Williams & Dunlop, "A generalization of the demagnetizing tensor for nonuniform magnetization," J. Geophysical Research-Solid Earth, **98**, 9551 (1993.)

Demag field (cont.)  
If cells are identical on a uniform grid, then  

$$\langle \mathbf{H}_{demag,i} \rangle = -\sum_{j} N_{i,j} \mathbf{M}_{j}$$
  
becomes  
 $\langle \mathbf{H}_{demag,i} \rangle = -\sum_{j} N_{i-j} \mathbf{M}_{j}$   
where FFT can be used to evalute  $\mathbf{H}_{demag,i}$ .  
(Note: Uniform grid;  $|M_i|$ 's can vary cell-to-cell.)

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RMS error = 118%

#### 10x10x1 oblate spheroid



Demag Field with Thickness Corrections



RMS error = 29%

General case  
Decompose  

$$H_{demag,i} = -\sum_{j} N_{i,j} M_j$$
into  

$$H_{demag,i} = -\sum_{j \in \Omega_{local}} N_{i,j} M_j - \sum_{j \in \Omega_{far}} N_{i,j} M_j$$
Handle  $\Omega_{far}$  via modified  $M_s$  and FFT,  $\Omega_{local}$  some other way.

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## General case (cont.)

Concept:

- Far field computed efficiently via FFT.
- Near field computed accurately.
- Restricted size keeps  $\Omega_{\text{local}} O(N)$ .

García-Cervera, Gimbutas, & E, "Accurate numerical methods for micromagnetics simulations with general geometries," *J. Comp. Physics*, **184**, 37 (2003).

# Local field computation

**Problem:** Implementing  $\Omega_{local}$  not so simple.

Idea: Use existing demag code to compute  $\Omega_{local}$ , but on a local, refined grid.











# Local field computation

During simulation run:

- Compute  $\mathbf{H}_{demag}$  as usual, with volume-modified |M|.
- For cells near boundary, include local corrections

$$\mathbf{H}_{\rm corr,i} = -\sum_{j\in\Omega_{\rm local_i}} K_{i,j} \mathbf{M}_j$$

• Correction is  $O(N_{\text{boundary}})$ 

Local correction, pushed Energy of correction is  $E_{i,j} \propto \mathbf{m}_i^T K_{i,j} \mathbf{m}_j$  $= \mathbf{m}_i^T K_{i,j}(\mathbf{m}_j - \mathbf{m}_i) + \mathbf{m}_i^T K_{i,j} \mathbf{m}_i.$ If  $|\mathbf{m}_i - \mathbf{m}_i|$  is small (exchange), then  $E_{i,j} \propto \mathbf{m}_i^T K_{i,j} \mathbf{m}_i$ which is a local anisotropy.









# Key points

- Edge mode sensitive only to edge effects
- Quantitative
- Robust quantity, does not involve critical field
- Experimentally relevant











### Summary

- Staircase demag artifact effectively corrected.
- Efficient far-field computation via FFT.
- Local correction coefficients computed using usual demag code.
- Local corrections have minimal run-time cost.
- Edge resonance test examined.
- Simple analytic + empirical edge anisotropy correction introduced.





$$\begin{split} \textbf{Exchange (uniform } \ell_{ex}) \\ \text{Usual exchange expression:} \\ \textbf{H}_{ij} &= \frac{2A}{\mu_0 \Delta_{ij}^2 M_s} (\textbf{m}_j - \textbf{m}_i) \\ \text{Volume-modified } M_s \text{ causes trouble if } M_s \approx 0. \\ \text{Instead, define} \\ \ell_{ex} &= \sqrt{\frac{2A}{\mu_0 M_s^2}} \quad \text{(fixed)} \\ \text{and} \\ \textbf{H}_{ij} &= \ell_{ex}^2 M_s (\textbf{m}_j - \textbf{m}_i) / \Delta_{ij}^2. \end{split}$$

### Edge mode refinement

Thin films magnetized in plane, perpendicular to edge.

Precession is localized at the edge by low fields

J. Jorzick et al., Phys. Rev. Lett. 88, 047204 (2002) J. P. Park et al., Phys. Rev. Lett. 89, 277201 (2002)



Edge mode frequencies fit Kittel expression with 2 parameters:

$$f(H_{\text{appl}}) = \frac{\mu_0 \gamma}{2\pi} \left[ (H_{\text{appl}} - H_x) (H_{\text{appl}} + H_z) \right]^{1/2}$$
Effective EDGE-normal anisotropy field

B. B. Maranville et al., J. Appl. Phys 99, 08C703 (2006).

R. D. McMichael and B. B. Maranville, Phys. Rev. B, 74, 024424 (2006).

#### Edge mode refinement

$$E_{\text{correction}} = \frac{1}{4}\mu_0 M_s^2 \cdot v(1-v) \cdot \left[K_x(\phi)m_x^2 + K_z(\phi)m_z^2\right]$$

"Correct" edge mode frequencies at  $\phi = 0$ ; no partial cells.

For each angle  $\phi$ , find  $K_{\chi}(\phi)$  and  $K_{\zeta}(\phi)$  such that

 $f(\phi, 0.1T) = f(0, 0.1T)$   $f(\phi, 0.5T) = f(0, 0.5T)$ 





Calculated for 350 nm square x 5 nm thick Py with 5 nm cubic cells.

